4. Erlangen TEM-School, 9-12 October 2012

This year already for the 4th time young researcher interested in transmission electron microscopy are invited to participate in the Erlangen TEM school, organised by the Center for Nanoanalyis and Electron Microscopy (CENEM) of the University of Erlangen-Nürnberg. The CENEM is equipped with CM30, CM300 as well as the state of the art Cc-corrected TITAN® TEMs operated at 80-300 kV. The school offers an excellent opportunity to become familiar with the theory and application of transmission electron microscopy techniques: sample preparation, diffraction techniques, diffraction contrast imaging, high resolution imaging and analytical TEM. Additionally a short introduction to advanced techniques like tomography and in-situ microscopy is planned. We intend to initiate discussions regarding the possibility of applying these new techniques in your research projects. The participants are therefore requested to send an abstract of about 150 words highlighting their motivation for participation and the research problems they want to solve by applying electron microscopic methods. The daily programme of the TEM School typically comprises a 2 hour lecture on the theory followed by group wise practical courses on sample preparation and microstructural/chemical analyses applying TEM in the laboratories of the CENEM. Therefore the number of participants is limited to 15 researchers.

School language: English

Fee: 150 €; No fee for Members of Erlangen Cluster of Excellence EAM, University of Erlangen and German Electron Microscopy Society (DGE)

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For application/abstract submission please fill in the attached form and send it to stefanie.spallek@ww.uni-erlangen.de.

Deadline for abstract submission: 3 August 2012

Notification of participation: 25 August 2012